

■ Features

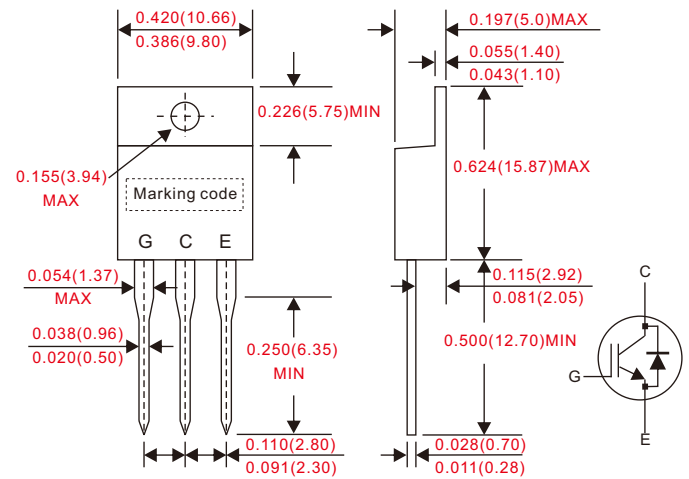
- Positive temperature Co-efficient for easy parallel operation.
- Short collector time-5us.
- High current capability.
- High input impedance.
- Low saturation voltage : $V_{CE(sat)} = 1.65@25^{\circ}C$.
- Fast switching : 20KHz ~ 40KHz($T_a = 25^{\circ}C$).
- Suffix "G" indicates Halogen-free part, ex. CI15T60G.

■ Mechanical data

- Epoxy : UL94-V0 rated flame retardant.
- Case : JEDEC TO-220AB molded plastic body.
- Terminals : Solder plated, solderable per MIL-STD-750, Method 2026.
- Polarity: As marked.
- Mounting Position : Any.
- Weight : Approximated 2.25 gram.

■ Outline

TO-220AB



Dimensions in inches and (millimeters)

■ Maximum ratings

Rating at 25°C ambient temperature unless otherwise specified. Single phase, half wave, 60Hz, resistive or inductive load. For capacitive load, derate current by 20%.

Parameter	Conditions	Symbol	CI15T60	UNIT
Marking code			CI15T60	
Collector to Emitter Voltage		V_{CE}	600	V
Collector Current	$T_c = 25^{\circ}C$	I_c	30	A
	$T_c = 100^{\circ}C$		15	
Pulsed collector current		I_{Cpuls}	45 ^{*2}	A
RBSOA current	$V_{CE} < 600V, T_J < 150^{\circ}C$	I_{Cpeak}	45 [*]	A
Diode Forward Current	$T_c = 25^{\circ}C$	I_F	20	A
	$T_c = 100^{\circ}C$		10	
Pulsed diode current		I_{Fpuls}	30	A
Gate to Emitter Voltage		V_{GE}	±20	V
Short collector time ³		t_{SC}	5	us
Power dissipation	$T_c = 125^{\circ}C$	P_{tot}	125 [*]	W
	$T_c = 100^{\circ}C$		65 [*]	
Operating Junction Temperature		T_J	-55 ~ +150	°C
Storage Temperature Range		T_{STG}	-55 ~ +150	°C

Note : 1. Test Standard to follow JESD-022 .
 2. Mark(*) is to estimate numerical value.
 3. Test Cycle < 1000 ; Test Timing > 1s.

■ Thermal characteristics						
PARAMETER	CONDITIONS	Symbol	MIN.	TYP.	MAX.	UNIT
Thermal Resistance	Junction to Case	$R_{\theta JC}$		0.75	1	K/W
Diode thermal resistance	chip case	$R_{\theta JCD}$		1.4	1.9	
Thermal Resistance	Junction to Ambient	$R_{\theta JA}$			62	
■ Electrical characteristics(AT $T_A=25^\circ\text{C}$ unless otherwise noted)						
On characteristics						
PARAMETER	CONDITIONS	Symbol	MIN.	TYP.	MAX.	UNIT
Collector to Emitter Breakdown Voltage	$V_{GE} = 0V, I_C = 0.2mA$	$V_{(BR)CES}$	600			V
Collector to Emitter Saturation Voltage	$V_{GE} = 15V, I_C = 15A$ $T_J = 25^\circ\text{C}$ $T_J = 150^\circ\text{C}$	$V_{CE(sat)}$		1.65 1.93	1.9	
Diode forward voltage	$V_{GE} = 0V, I_F = 10A$ $T_J = 25^\circ\text{C}$ $T_J = 150^\circ\text{C}$	V_F		1.75 1.40		
Gate threshold voltage	$I_C = 0.21mA, V_{CE} = V_{GE}$	$V_{GE(th)}$	4.4	5.25	6	
Collector Cut-Off Current	$V_{CE} = 600V, V_{GE} = 0V$ $T_J = 25^\circ\text{C}$ $T_J = 150^\circ\text{C}$	I_{CES}			40 1000	μA
G-E Leakage Current	$V_{CE} = 0V, V_{GE} = 20V$	I_{GES}			100	nA
Transconductance	$V_{CE} = 20V, I_C = 15A$	gFS		8.6		S
Dynamic characteristics						
PARAMETER	CONDITIONS	Symbol	MIN.	TYP.	MAX.	UNIT
Input Capacitance	$V_{CE} = 25V$	C_{iss}		1020		pF
Output Capacitance	$V_{GE} = 0V$	C_{oss}		74		
Reverse Transfer Capacitance	$f = 1MHz$	C_{fss}		35		
Total Gate Charge	$V_{CC} = 480V, I_C = 15A, V_{GE} = 15V$	Q_G		76		nC
Short Current	$V_{CC} = 400V, V_{GE} = 15V$	I_{sc}		120		A

Switching characteristics							
PARAMETER	CONDITIONS	Symbol	MIN.	TYP.	MAX.	UNIT	
Turn-On Delay Time	$T_J = 25^\circ\text{C}$ $V_{CC} = 400\text{V}, I_C = 15\text{A}$	$t_{d(on)}$		23		ns	
Rise Time		t_r		20			
Turn-Off Delay Time		$t_{d(off)}$		139			
Fall Time		t_f		42			
Turn-On Switching Loss	$L_{load} = 500\mu\text{H}$	E_{on}		0.36		mJ	
Turn-Off Switching Loss		E_{off}		0.32			
Total Switching Loss		E_{ts}		0.68			
Turn-On Delay Time	$T_J = 150^\circ\text{C}$ $V_{CC} = 400\text{V}, I_C = 15\text{A}$	$t_{d(on)}$		27		ns	
Rise Time		t_r		25			
Turn-Off Delay Time		$t_{d(off)}$		155			
Fall Time		t_f		108			
Turn-On Switching Loss	$L_{load} = 500\mu\text{H}$	E_{on}		0.37		mJ	
Turn-Off Switching Loss		E_{off}		0.46			
Total Switching Loss		E_{ts}		0.83			
Switching characteristics							
PARAMETER	CONDITIONS	Symbol	MIN.	TYP.	MAX.	UNIT	
Reverse recovery time	$T_J = 25^\circ\text{C}$ $V_{CC} = 400\text{V}, I_F = 10\text{A}$	t_{rr}		45		ns	
Reverse recovery charge		Q_{rr}		73		nC	
Repetitive Peak Reverse Current	$diF/dt = 200\text{A}/\mu\text{s}$	I_{rrm}		4		A	
Reverse recovery time	$T_J = 150^\circ\text{C}$ $V_{CC} = 400\text{V}, I_F = 10\text{A}$	t_{rr}		92		ns	
Reverse recovery charge		Q_{rr}		371		nC	
Repetitive Peak Reverse Current		$diF/dt = 200\text{A}/\mu\text{s}$	I_{rrm}		8		A

Rating and characteristic curves

Fig 1. SAFE OPERATION AREA

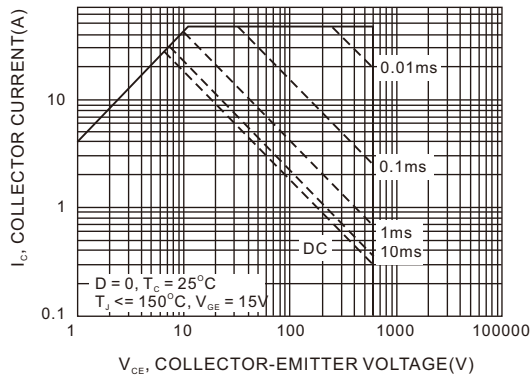


Fig 2. TYPICAL OUTPUT CHARACTERISTICS

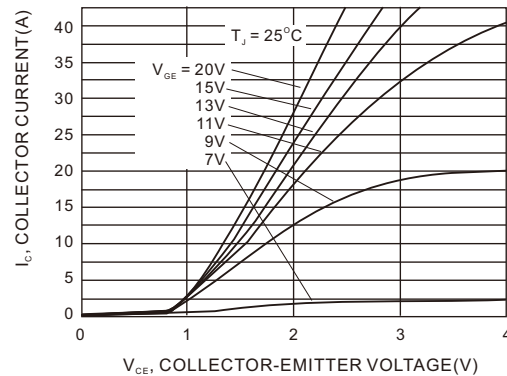


Fig 3. TYPICAL OUTPUT CHARACTERISTICS

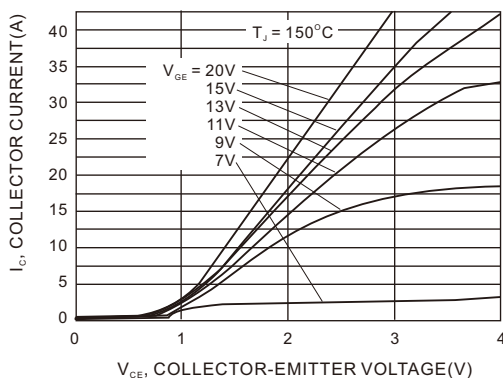


Fig 4. TYPICAL TRANSFER CHARACTERISTIC

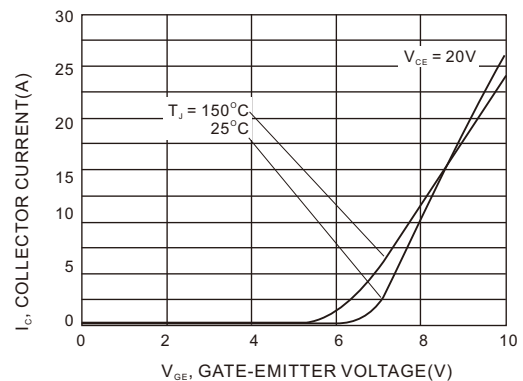


Fig 5. TYPICAL COLLECTOR-EMITTER SATURATION VOLTAGE AS A FUNCTION OF JUNCTION TEMPERATURE

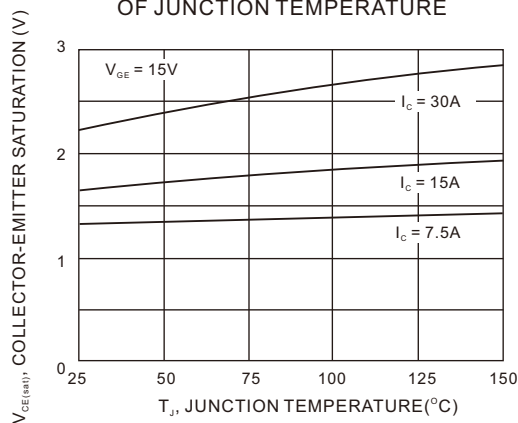


Fig 6. TYPICAL SWITCHING TIMES AS A FUNCTION OF COLLECTOR CURRENT

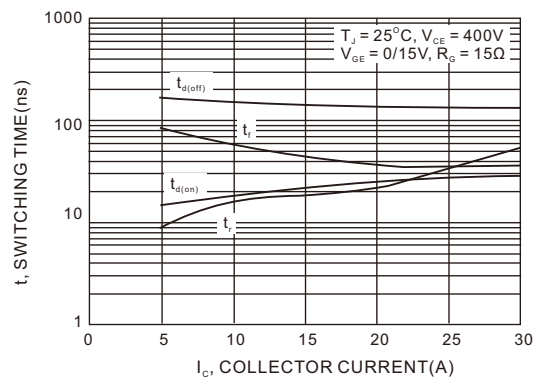


Fig 7. TYPICAL SWITCHING TIMES AS A FUNCTION OF GATE RESISTOR

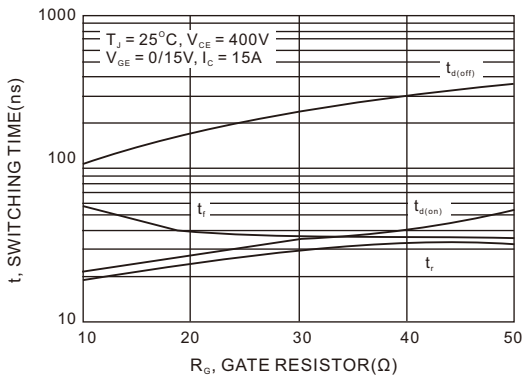


Fig 8. TYPICAL SWITCHING TIMES AS A FUNCTION OF JUNCTION TEMPERATURE

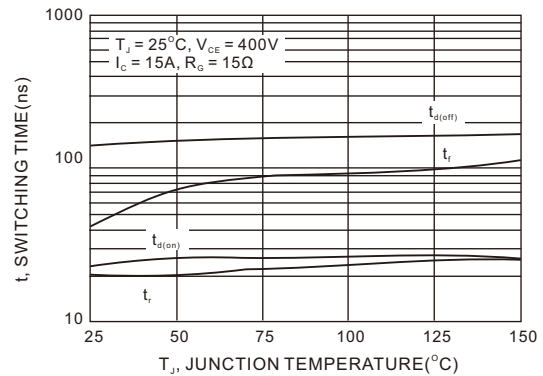


Fig 9. GATE-EMITTER THRESHOLD VOLTAGE AS A FUNCTION OF JUNCTION TEMPERATURE

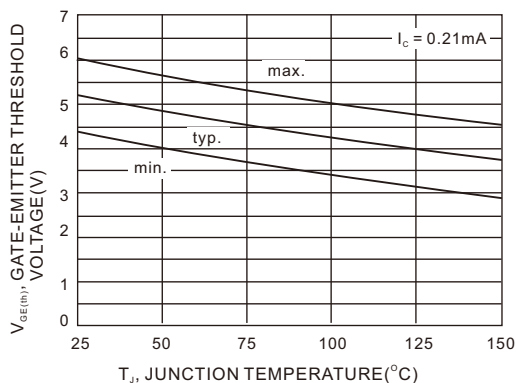


Fig 10. TYPICAL SWITCHING ENERGY LOSSES AS A FUNCTION OF COLLECTOR CURRENT

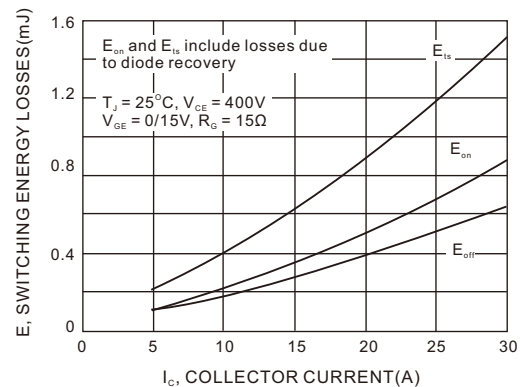


Fig 11. TYPICAL SWITCHING ENERGY LOSSES AS A FUNCTION OF GATE RESISTOR

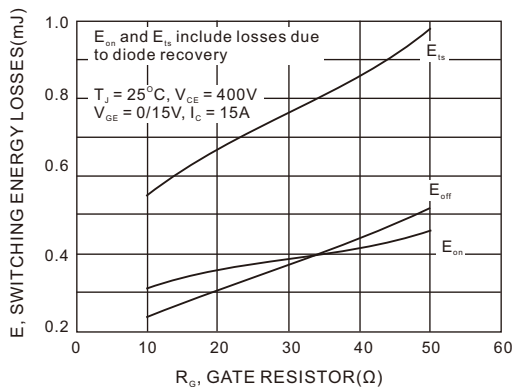


Fig 12. TYPICAL SWITCHING ENERGY LOSSES AS A FUNCTION OF COLLECTOR-EMITTER VOLTAGE

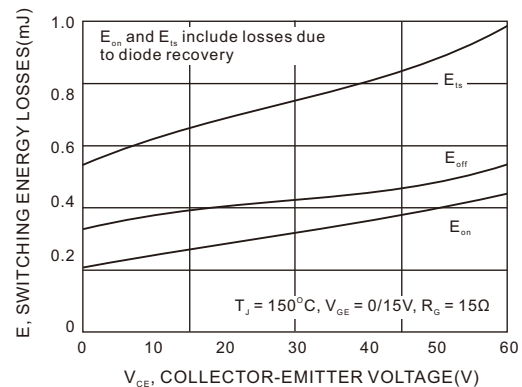


Fig 13. TYPICAL GATE CHARGE

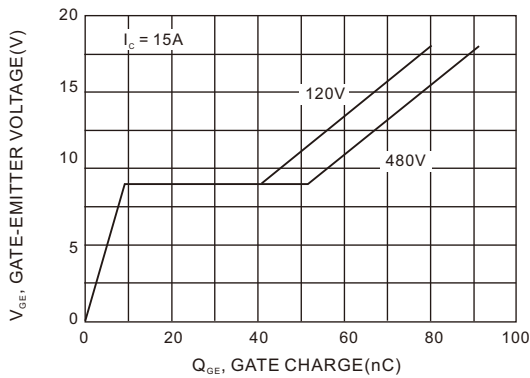


Fig 14. TYPICAL CAPACITANCE AS A FUNCTION OF COLLECTOR-EMITTER VOLTAGE

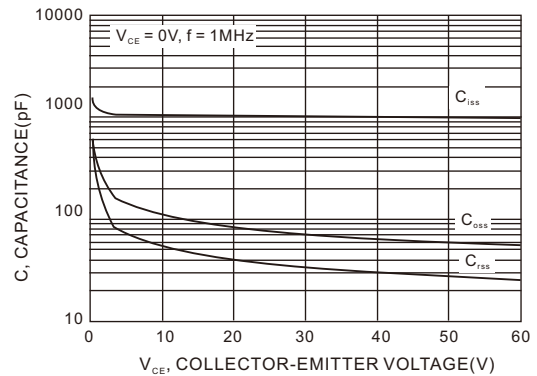


Fig 15. TYPICAL SHORT CIRCUIT COLLECTOR AS A FUNCTION OF GATE-EMITTER VOLTAGE

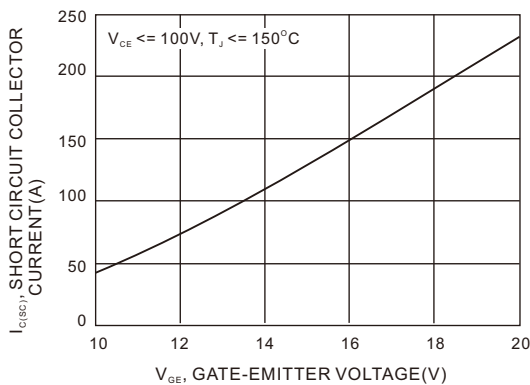


Fig 16. IGBT TRANSIENT THERMAL RESISTANCE

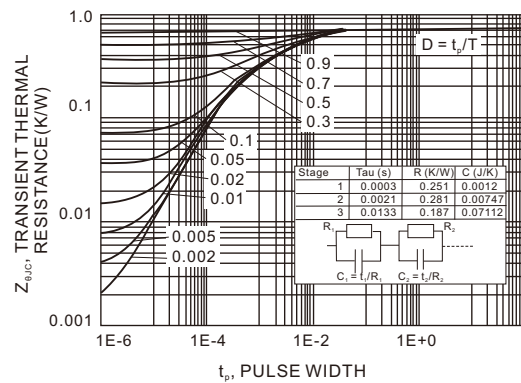


Fig 17. DIODE TRANSIENT THERMAL RESISTANCE

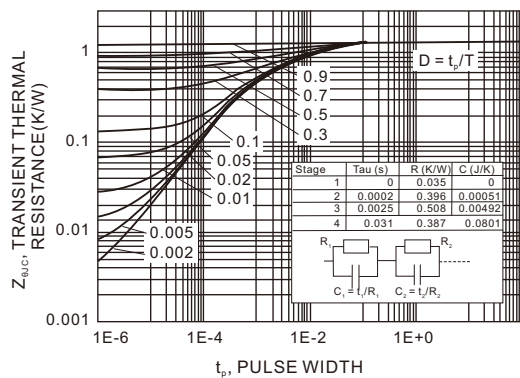


Fig 18. TYPICAL REVERSE RECOVERY TIME AS A FUNCTION OF DIODE CURRENT SLOPE

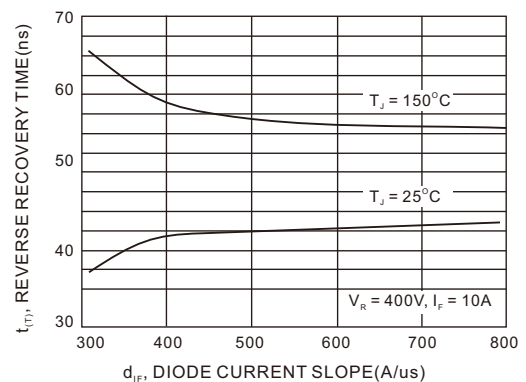


Fig 19. TYPICAL REVERSE RECOVERY CHARGE AS A FUNCTION OF DIODE CURRENT SLOPE

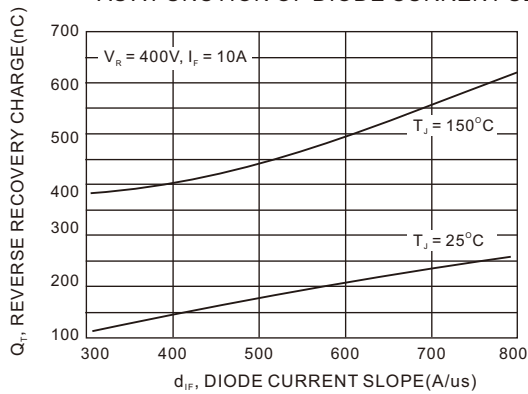


Fig 20. TYPICAL REVERSE RECOVERY CURRENT AS A FUNCTION OF DIODE CURRENT SLOPE

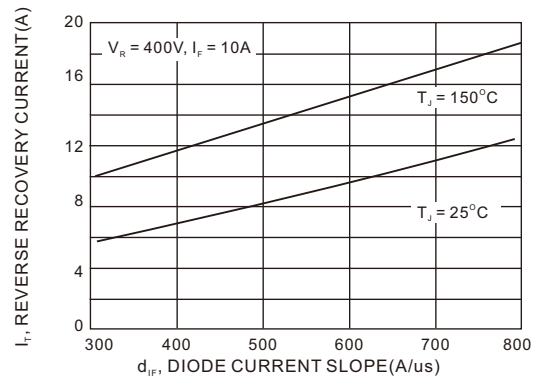


Fig 21. TYPICAL DIODE PEAK RATE OF FALL OF REVERSE RECOVERY CURRENT AS A FUNCTION OF DIODE CURRENT SLOPE

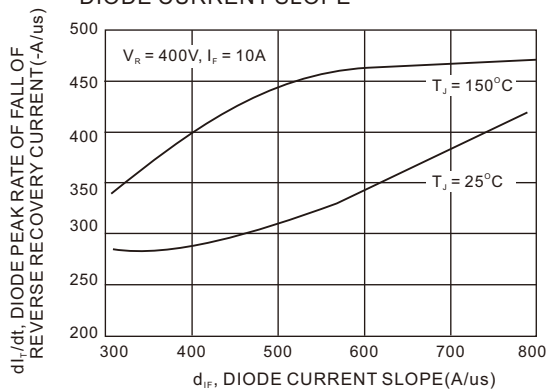


Fig 22. TYPICAL DIODE FORWARD CURRENT AS A FUNCTION OF FORWARD VOLTAGE

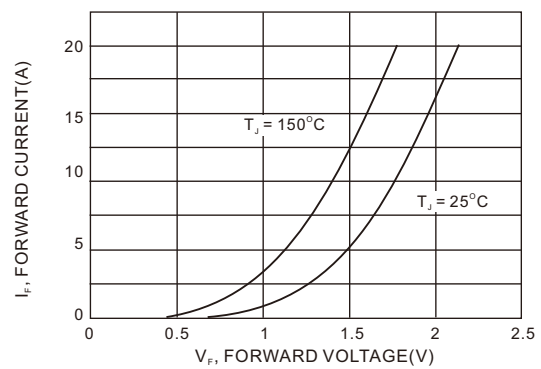


Fig 23. TYPICAL DIODE FORWARD VOLTAGE AS A FUNCTION OF JUNCTION TEMPERATURE

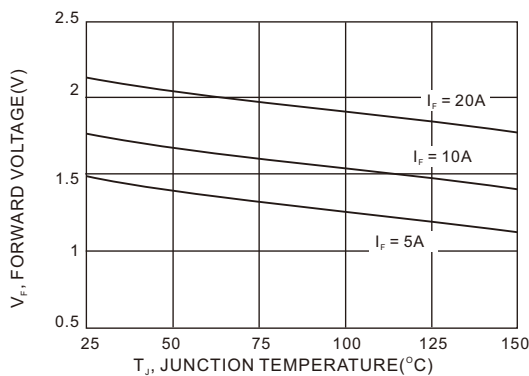


Fig A. DYNAMIC TEST CIRCUIT

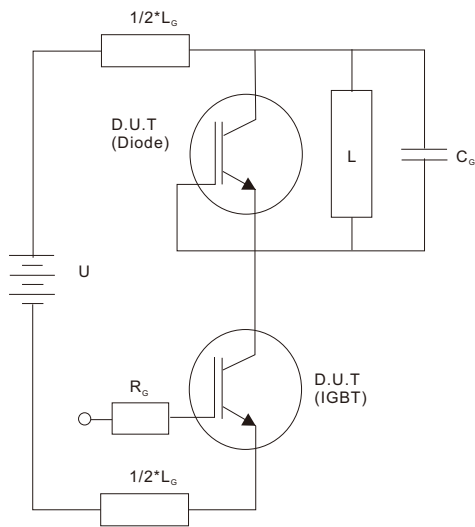


Fig B. DEFINITION OF SWITCHING LOSSES

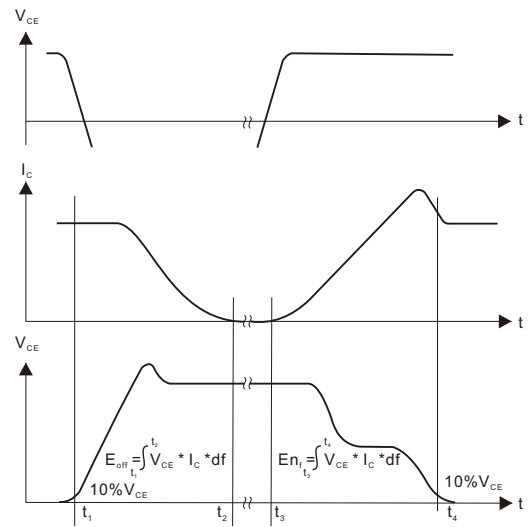


Fig C. DEFINITION OF DIODES SWITCHING CHARACTERISTICS

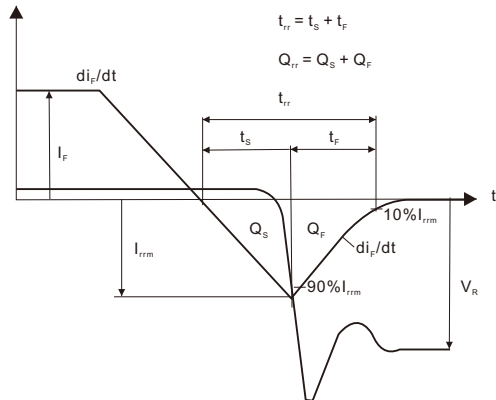
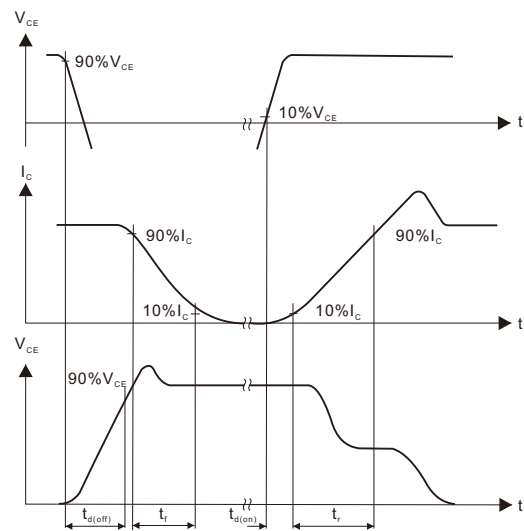


Fig D. DEFINITION OF SWITCHING TIMES



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